

RoHS

COMPLIANT HALOGEN

FREE

ECH8601M-VB Datasheet

Dual N-Channel 20 V (D-S) MOSFET

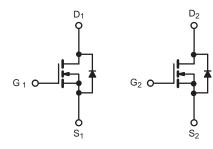
PRODUC	DUCT SUMMARY			
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)	
20	0.017 at V _{GS} = 4.5 V	4.8	1.8 nC	
20	0.023 at V _{GS} = 2.5 V	3.3	1.0110	

FEATURES

- Halogen-free According to IEC 61249-2-21
 Definition
- Trench Power MOSFET
- 100 % R_g Tested
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

- Load Switch for Portable Applications
- DC/DC Converters



N-Channel MOSFET

N-Channel MOSFET

Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	20	V
Gate-Source Voltage		V _{GS}	± 12	v
	T _C = 25 °C		4.8	
Continuous Drain Current ($T_1 = 150 \ ^{\circ}C$)	T _C = 70 °C	I _D	3	
	T _A = 25 °C		3.4 ^{b, c}	
	T _A = 70 °C		2.7 ^{b, c}	A
Pulsed Drain Current		I _{DM}	15	
	T _C = 25 °C		1.17	
Continuous Source-Drain Diode Current	T _A = 25 °C	Is	0.95 ^{b, c}	
	T _C = 25 °C		1.4	
Maximum Power Dissipation	T _C = 70 °C	P _D	0.9	w
	T _A = 25 °C		1.14 ^{b, c}	••
	T _A = 70 °C	1 [0.73 ^{b, c}	
Operating Junction and Storage Temperatur	e Range	T _J , T _{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Tempera	ature) ^{d, e}		260	

THERMAL RESISTANCE RATINGS

Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	$t \le 5 s$	R _{thJA}	93	110	°C/W	
Maximum Junction-to-Foot	Steady State	R _{thJF}	75	90	°C/W	

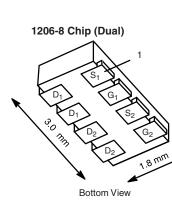
Notes:

a. $T_C = 25 \ ^{\circ}C.$

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 5 s.

d. Maximum under steady state conditions is 150 $^{\circ}\text{C/W}.$





Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	1 -				1		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L 050 A		29			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 4		- mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.2		2.2	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
		$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1		
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 ^{\circ}\text{C}$			10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	10			Α	
		V _{GS} = 4.5 V, I _D = 3.4 A		0.017		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 2.5 \text{ V}, \text{ I}_{D} = 3.0 \text{ A}$		0.023			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 3.4 A		10		S	
Dynamic ^b					1		
Input Capacitance	C _{iss}			235			
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		45		pF	
Reverse Transfer Capacitance	C _{rss}			16			
Table Oats Observe		V_{DS} = 15 V, V_{GS} = 10 V, I_{D} = 3.4 A		3.7	6		
Total Gate Charge	Qg			1.8	3		
Gate-Source Charge	Q _{gs}	V_{DS} = 15 V, V_{GS} = 4.5 V, I_{D} = 3.4 A		0.74		nC	
Gate-Drain Charge	Q _{gd}			0.42			
Gate Resistance	Rg	f = 1 MHz	1	5	10	Ω	
Turn-On Delay Time	t _{d(on)}			10	20		
Rise Time	t _r	V_{DD} = 15 V, R_L = 5.6 Ω		15	30		
Turn-Off Delay Time	t _{d(off)}	$\text{I}_\text{D}{\cong}2.7$ A, V_GEN = 4.5 V, R_g = 1 Ω		10	20		
Fall Time	t _f			10	20		
Turn-On Delay Time	t _{d(on)}			5	10	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 5.6 Ω		15	30	1	
Turn-Off Delay Time	t _{d(off)}	$\text{I}_\text{D}\cong$ 2.7 A, V_GEN = 10 V, R_g = 1 Ω		10	20		
Fall Time	t _f			10	20		
Drain-Source Body Diode Characteristic	cs				•	•	
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			1.17	Δ	
Pulse Diode Forward Current	I _{SM}				15	A	
Body Diode Voltage	V _{SD}	$I_{S} = 2.7 \text{ A}, V_{GS} = 0 \text{ V}$		0.85	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			10	20	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L = 2.7 A dV/dt = 100 A/vo T = 25 eV		4	10	nC	
Reverse Recovery Fall Time	t _a	I _F = 2.7 A, dl/dt = 100 A/µs, T _J = 25 °C		6			
Reverse Recovery Rise Time	t _b			4		ns	

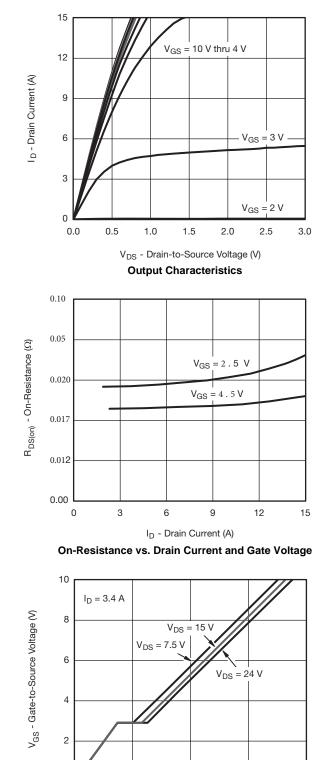
Notes:

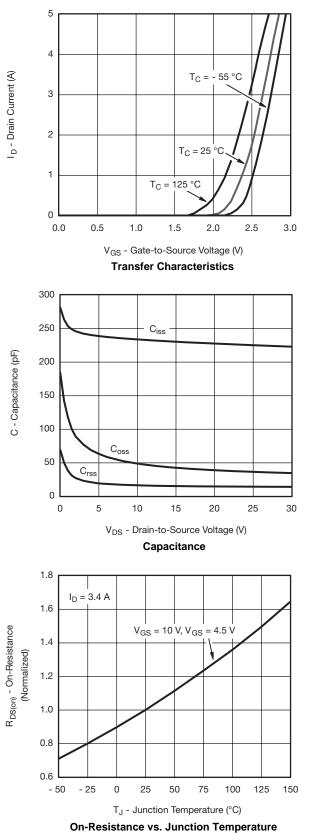
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.







服务热线:400-655-8788

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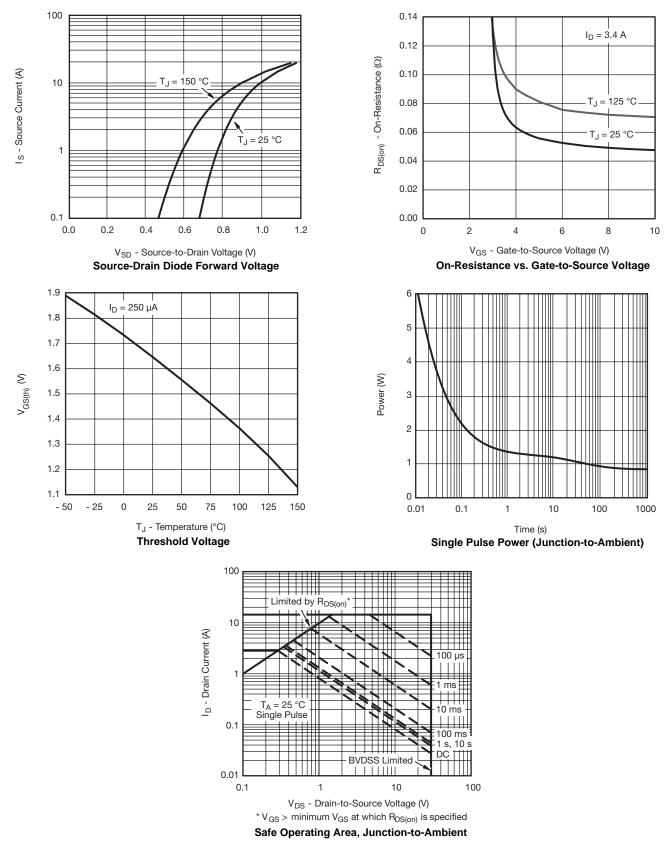
Q_q - Total Gate Charge (nC)

Gate Charge

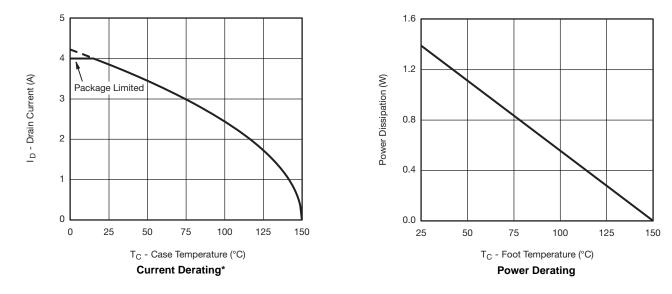
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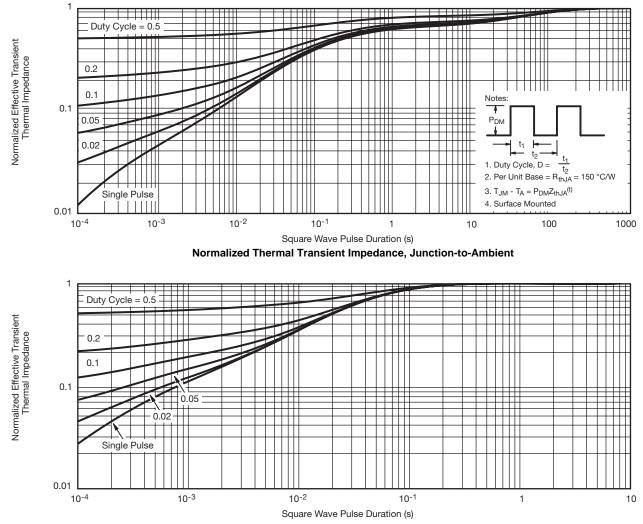






* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



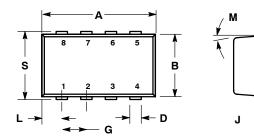


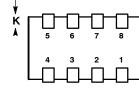
Normalized Thermal Transient Impedance, Junction-to-Foot

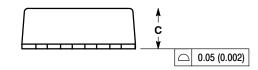


PACKAGE DIMENSIONS

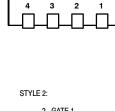
ChipFET CASE 1206A-03 **ISSUE D**







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2.	GATE 1
5. 6. 7.	GATE 2 DRAIN 2 DRAIN 2 DRAIN 1 DRAIN 1

1.	DIMENSIONING AND TOLERANCING PER ANSI
	V44 EN 4000

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
 MOLD GATE BURRS SHALL NOT EXCEED 0.13 MM PER SIDE.
 LEADFRAME TO MOLDED BODY OFFSET IN HORIZONTAL AND VERTICAL SHALL NOT EXCEED 0.08 MM.
 DIMENSIONS A AND B EXCLUSIVE OF MOLD GATE BURRS.
 NOMOLD FLASH ALLOWED ON THE TOP AND BOTTOM LEAD SURFACE.
 1206A-01 AND 1206A-02 OBSOLETE. NEW STANDARD IS 1206A-03.

	MILLIN	IETERS	INCHES		
DIM	MIN MAX		MIN	MAX	
Α	2.95	3.10	0.116	0.122	
В	1.55	1.70	0.061	0.067	
C	1.00	1.10	0.039	0.043	
D	0.25	0.35	0.010	0.014	
G	0.65	5 BSC	0.025 BSC		
J	0.10	0.20	0.004	0.008	
K	0.28	0.42	0.011	0.017	
Ľ	0.55	5 BSC	0.022 BSC		
М	5 ° NOM		5 ° NOM		
S	1.80	2.00	0.072	0.080	



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